

ISO7240CF, ISO7240C, ISO7240M ISO7241C, ISO7241M ISO7242C, ISO7242M

SLLS868L - SEPTEMBER 2007-REVISED JANUARY 2010

### HIGH SPEED QUAD DIGITAL ISOLATORS

Check for Samples: ISO7240CF, ISO7240C, ISO7240M, ISO7241C, ISO7241M, ISO7242C, ISO7242M

#### **FEATURES**

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- Selectable Failsafe Output (ISO7240CF)
- 25 and 150-Mbps Signaling Rate Options
  - Low Channel-to-Channel Output Skew;
     1 ns Max
  - Low Pulse-Width Distortion (PWD);2 ns Max
  - Low Jitter Content; 1 ns Typ at 150 Mbps
- Typical 25-Year Life at Rated Working Voltage (see application note SLLA197 and Figure 17)
- 4000-V<sub>peak</sub> Isolation, 560-V<sub>peak</sub> V<sub>IORM</sub>
  - UL 1577, IEC 60747-5-2 (VDE 0884, Rev 2), IEC 61010-1, IEC 60950-1 and CSA Approved

- 4 kV ESD Protection
- Operate With 3.3-V or 5-V Supplies
- High Electromagnetic Immunity (see application report SLLA181)
- -40°C to 125°C Operating Range

#### **APPLICATIONS**

- Industrial Fieldbus
- Computer Peripheral Interface
- Servo Control Interface
- Data Acquisition

#### **DESCRIPTION**

The ISO7240, ISO7241 and ISO7242 are quad-channel digital isolators with multiple channel configurations and output enable functions. These devices have logic input and output buffers separated by Tl's silicon dioxide (SiO<sub>2</sub>) isolation barrier. Used in conjunction with isolated power supplies, these devices block high voltage, isolate grounds, and prevent noise currents from entering the local ground and interfering with or damaging sensitive circuitry.

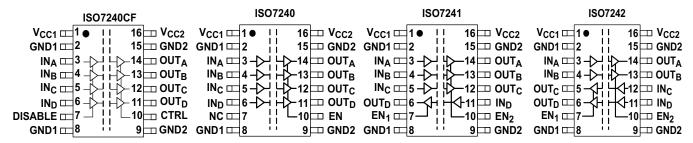
The ISO7240 has all four channels in the same direction while the ISO7241 has three channels the same direction and one channel in opposition. The ISO7242 has two channels in each direction.

The C option devices have TTL input thresholds and a noise-filter at the input that prevents transient pulses from being passed to the output of the device. The M option devices have CMOS Vcc/2 input thresholds and do not have the input noise-filter or the additional propagation delay.

The ISO7240CF has an input disable function on pin 7, and a selectable high or low failsafe-output function with the CTRL pin (pin 10). The failsafe-output is a logic high when a logic-high is placed on the CTRL pin or it is left unconnected. If a logic-low signal is applied to the CTRL pin, the failsafe-output becomes a logic-low output state. The ISO7240CF input disable function prevents data from being passed across the isolation barrier to the output. When the inputs are disabled, the outputs are set by the CTRL pin.

These devices may be powered from either 3.3-V or 5-V supplies on either side in any 3.3-V / 3.3-V, 5-V / 5-V, 5-V / 3.3-V, or 3.3-V / 5-V combination. Note that the signal input pins are 5-V tolerant regardless of the voltage supply level being used.

These devices are characterized for operation over the ambient temperature range of -40°C to 125°C.





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

Table 1. Device Function Table ISO724x (1)

INPUT V <sub>CC</sub>	OUTPUT V <sub>CC</sub>	INPUT (IN)	OUTPUT ENABLE (EN)	OUTPUT (OUT)
		Н	H or Open	Н
DU	PU	L	H or Open	L
PU		X	Г	Z
		Open	H or Open	Н
PD	PU	X	H or Open	Н
PD	PU	X	L	Z

(1) PU = Powered Up; PD = Powered Down; X = Irrelevant; H = High Level; L = Low Level

#### Table 2. ISO7240CF Function Table

V <sub>CC1</sub>	V <sub>CC2</sub>	DATA INPUT (IN)	DISABLE INPUT (DISABLE)	FAILSAFE CONTROL INPUT (CTRL)	DATA OUTPUT (OUT)
PU	PU	Н	L or Open	X	Н
PU	PU	L	L or Open	X	L
Х	PU	X	Н	H or Open	Н
Х	PU	X	Н	L	L
PD	PU	X	X	H or Open	Н
PD	PU	X	X	L	L

#### **AVAILABLE OPTIONS**

PRODUCT	SIGNALING RATE	INPUT THRESHOLD	CHANNEL CONFIGURATION	MARKED AS	ORDERING NUMBER <sup>(1)</sup>		
ISO7240CDW	25 Mbps	~1.5 V (TTL)		ISO7240C	ISO7240CDW (rail)		
1307240CDW	25 Misps	(CMOS compatible)		13072400	ISO7240CDWR (reel)		
ISO7240CF	25 Mbno	~1.5 V (TTL)	4/0	ISO7240CF	ISO7240CFDW (rail)		
1507240CF	25 Mbps	(CMOS compatible)	) 4/0 150724	1507240CF	ISO7240CFDWR (reel)		
1007040MDW	150 Mbpo	Vee/2 (CMOC)		ISO7240M	ISO7240MDW (rail)		
ISO7240MDW	150 Mbps	Vcc/2 (CMOS)		1507240101	ISO7240MDWR (reel)		
ISO7241CDW	25 Mbno	~1.5 V (TTL)		ISO7241C	ISO7241CDW (rail)		
1507241CDW	25 Mbps	(CMOS compatible)	3/1	15072410	ISO7241CDWR (reel)		
ISO7241MDW	150 Mbpo	Vee/2 (CMOC)	3/1	ISO7241M	ISO7241MDW (rail)		
150724 TIVIDVV	150 Mbps	Vcc/2 (CMOS)		1507241101	ISO7241MDWR (reel)		
ICO7242CDW	~1.5 V (TTL)		~1.5 V (TTL)		~1.5 V (TTL)		ISO7242CDW (rail)
ISO7242CDW	25 Mbps	(CMOS compatible)	2/2	ISO7242C	ISO7242CDWR (reel)		
ICO7242MDW	150 Mbpo	\/aa/2 (CMOC)	2/2	100724214	ISO7242MDW (rail)		
ISO7242MDW	150 Mbps	Vcc/2 (CMOS)		ISO7242M	ISO7242MDWR (reel)		

<sup>(1)</sup> For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.





#### ABSOLUTE MAXIMUM RATINGS(1)

					VALUE	UNIT	
$V_{CC}$	Supply voltage	ge <sup>(2)</sup> , V <sub>CC1</sub> , V <sub>CC2</sub>			-0.5 to 6	V	
$V_{I}$	Voltage at IN	, OUT, EN, DISABLE, CTRL			-0.5 to 6	V	
Io						mA	
		Human Body Model	JEDEC Standard 22, Test Method A114-C.01		±4	kV	
ESD	Electrostatic discharge	Field-Induced-Charged Device Model	JEDEC Standard 22, Test Method C101	All pins	±1		
		Machine Model	ANSI/ESDS5.2-1996		±200	V	
$T_{J}$	Maximum jun		170	°C			

<sup>(1)</sup> Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### RECOMMENDED OPERATING CONDITIONS

			MIN	TYP	MAX	UNIT
$V_{CC}$	Supply voltage <sup>(1)</sup> , V <sub>CC1</sub> , V <sub>CC2</sub>		3.15		5.5	V
I <sub>OH</sub>	High-level output current				4	mA
I <sub>OL</sub>	Low-level output current		-4			mA
	Lancet made a confedition	ISO724xC	40			
t <sub>ui</sub>	Input pulse width	ISO724xM	6.67	5		ns
4 //	O. I.	ISO724xC	0	30 <sup>(2)</sup>	25	
1/t <sub>ui</sub>	<sub>ii</sub> Signaling rate	ISO724xM	0	200(2)	150	Mbps
$V_{IH}$	High-level input voltage (IN)	ISO724xC ISO724xM ISO724xM	0.7 V <sub>CC</sub>		V <sub>CC</sub>	V
$V_{IL}$	Low-level input voltage (IN)	ISO724xM	0		0.3 V <sub>CC</sub>	V
V <sub>IH</sub>	High-level input voltage (IN, DISABLE, CTRL, EN)	100704.0	2		V <sub>CC</sub>	V
$V_{IL}$	Low-level input voltage (IN, DISABLE, CTRL, EN)	ISO724xC	0		0.8	V
T <sub>J</sub>	Junction temperature				150	°C
Н	External magnetic field-strength immunity per IEC 610 certification	xternal magnetic field-strength immunity per IEC 61000-4-8 and IEC 61000-4-9				A/m

<sup>(1)</sup> For the 5-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 4.5 V to 5.5 V. For the 3-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 3.15 V to 3.6 V.

#### IEC 60747-5-2 INSULATION CHARACTERISTICS(1)

	PARAMETER	TEST CONDITIONS	SPECIFICATIONS	UNIT
V <sub>IORM</sub>	Maximum working insulation voltage		560	V
		After Input/Output Safety Test Subgroup 2/3 V <sub>PR</sub> = V <sub>IORM</sub> × 1.2, t = 10 s, Partial discharge < 5 pC	672	V
$V_{PR}$	Input to output test voltage	Method a, V <sub>PR</sub> = V <sub>IORM</sub> × 1.6, Type and sample test with t = 10 s, Partial discharge < 5 pC	896	V
		Method b1, $V_{PR} = V_{IORM} \times 1.875$ , 100 % Production test with t = 1 s, Partial discharge < 5 pC	1050	V
V <sub>IOTM</sub>	Transient overvoltage	t = 60 s	4000	V
R <sub>S</sub>	Insulation resistance	V <sub>IO</sub> = 500 V at T <sub>S</sub>	>10 <sup>9</sup>	Ω
	Pollution degree		2	

<sup>(1)</sup> Climatic Classification 40/125/21

<sup>(2)</sup> All voltage values are with respect to network ground terminal and are peak voltage values.

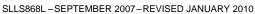
<sup>(2)</sup> Typical value at room temperature and well-regulated power supply.



## ELECTRICAL CHARACTERISTICS: V<sub>CC1</sub> and V<sub>CC2</sub> at 5-V<sup>(1)</sup> OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPL	Y CURRENT					<u>'</u>	
	10070400/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels, no load,		1	3	A
	ISO7240C/M	25 Mbps	EN <sub>2</sub> at 3 V		7	10.5	mA
	ISO7241C/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels, no load,		6.5	11	mΛ
I <sub>CC1</sub>	1507241C/W	25 Mbps	EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V		12	18	mA
	ISO7242C/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels, no load,		10	16	mA
	15072420/W	25 Mbps	EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V		15	24	
	10070400/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels, no load,		15	22	•
	ISO7240C/M	25 Mbps	EN <sub>2</sub> at 3 V		17	25	mA
	ISO7241C/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels, no load,		13	20	A
I <sub>CC2</sub>	1507241C/W	25 Mbps	EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V		18	28	mA
	10070400/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels, no load,		10	16	A
	ISO7242C/M	25 Mbps	EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V		15	24	mA
ELECTI	RICAL CHARACTERISTICS						
l <sub>OFF</sub>	Sleep mode output curren	t	EN at 0 V, Single channel		0		μА
V	Lliab lovel output voltage		I <sub>OH</sub> = -4 mA, See Figure 1	$V_{CC} - 0.8$	V <sub>CC</sub> - 0.8 V <sub>CC</sub> - 0.1		V
V <sub>OH</sub>	High-level output voltage		I <sub>OH</sub> = -20 μA, See Figure 1	V <sub>CC</sub> - 0.1			V
\/	Low lovel output voltage		I <sub>OL</sub> = 4 mA, See Figure 1			0.4	V
$V_{OL}$	Low-level output voltage		I <sub>OL</sub> = 20 μA, See Figure 1			0.1	V
$V_{I(HYS)}$	Input voltage hysteresis				150		mV
I <sub>IH</sub>	High-level input current		INI from 0 \/ to \/			10	^
I <sub>IL</sub>	Low-level input current		IN from 0 V to V <sub>CC</sub>	-10			μΑ
Cı	Input capacitance to groun	nd	IN at $V_{CC}$ , $V_I = 0.4 \sin (4E6\pi t)$		2		pF
CMTI	Common-mode transient	mmunity	V <sub>I</sub> = V <sub>CC</sub> or 0 V, See Figure 5	25	50		kV/μs

<sup>(1)</sup> For the 5-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 4.5 V to 5.5 V. For the 3-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 3.15 V to 3.6 V.







## SWITCHING CHARACTERISTICS: $V_{\text{CC1}}$ and $V_{\text{CC2}}$ at 5-V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	ISO724xC		18		42	20
PWD	Pulse-width distortion <sup>(1)</sup>  t <sub>PHL</sub> - t <sub>PLH</sub>	130724xC	See Figure 4			2.5	ns
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	100724vM	See Figure 1	10		23	20
PWD	Pulse-width distortion <sup>(1)</sup>  t <sub>PHL</sub> - t <sub>PLH</sub>	ISO724xM			1	2	ns
	Don't to mant alliance (2)	ISO724xC				8	
t <sub>sk(pp)</sub>	Part-to-part skew <sup>(2)</sup>	ISO724xM			0	3	ns
	Observation of a second section (3)	ISO724xC				2	
t <sub>sk(o)</sub>	Channel-to-channel output skew (3)	ISO724xM			0	1	ns
t <sub>r</sub>	Output signal rise time		0		2		
t <sub>f</sub>	Output signal fall time		See Figure 1		2		ns
t <sub>PHZ</sub>	Propagation delay, high-level-to-high-imp	edance output			15	20	
t <sub>PZH</sub>	Propagation delay, high-impedance-to-hiç	gh-level output			15	20	
t <sub>PLZ</sub>	Propagation delay, low-level-to-high-impe	edance output	See Figure 2		15	20	ns
t <sub>PZL</sub>	Propagation delay, high-impedance-to-lov	w-level output			15	20	
t <sub>fS</sub>	Failsafe output delay time from input pow	er loss	See Figure 3		12		μS
t <sub>wake</sub>	Wake time from input disable		See Figure 4		15		μS
t <sub>jit(pp)</sub>	Peak-to-peak eye-pattern jitter	ISO724xM	150 Mbps NRZ data input, Same polarity input on all channels, See Figure 6		1		ns

<sup>(1)</sup> Also referred to as pulse skew.

<sup>(2)</sup> t<sub>sk(pp)</sub> is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

<sup>(3)</sup>  $t_{sk(0)}$  is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.



## ELECTRICAL CHARACTERISTICS: V<sub>CC1</sub> at 5-V, V<sub>CC2</sub> at 3.3-V<sup>(1)</sup> OPERATION

	PARAMETE	ΕR	TEST CONDIT	IONS	MIN	TYP	MAX	UNIT
SUPPL	Y CURRENT				*		*	
	10070400/M	Quiescent	\/ \/ \	a land EN at 2.1/		1	3	A
	ISO7240C/M	25 Mbps	$V_I = V_{CC}$ or 0 V, All channels, r	10 10ad, EN <sub>2</sub> at 3 V		7	10.5	mA
	ISO7241C/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels, r	io load, EN₁ at 3 V,		6.5	11	A
I <sub>CC1</sub>	1507241C/M	25 Mbps	EN <sub>2</sub> at 3 V	•		12	18	mA
	ISO7242C/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels, r	io load, EN <sub>1</sub> at 3 V,		10	16	mA
	13072420/101	25 Mbps	EN <sub>2</sub> at 3 V	•		15	24	mA
	ICO7040C/M	Quiescent	\/ \/ or 0 \/ All abannala r	solood FN at 2 V		9.5	15	A
	ISO7240C/M	25 Mbps	$V_I = V_{CC}$ or 0 V, All channels, r	10 10ad, EN <sub>2</sub> at 3 V		10.5	17	mA
	ISO7241C/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels, r	io load, EN₁ at 3 V,		8	13	mΛ
$I_{CC2}$	1507241C/M	25 Mbps	EN <sub>2</sub> at 3 V		11.5	18	mA	
	ISO7242C/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels, r	no load, EN₁ at 3 V,		6	10	A
	25 Mbps		EN <sub>2</sub> at 3 V			9	14	mA
ELECTI	RICAL CHARACTE	ERISTICS						
l <sub>OFF</sub>	Sleep mode outp	ut current	EN at 0 V, Single channel			0		μΑ
				ISO7240	V <sub>CC</sub> - 0.4			
$V_{OH}$	High-level output	voltage	I <sub>OH</sub> = -4 mA, See Figure 1	ISO724x (5-V side)	V <sub>CC</sub> - 0.8			V
			$I_{OH} = -20 \mu A$ , See Figure 1		V <sub>CC</sub> - 0.1			
\/	Law layed autaut	voltogo	I <sub>OL</sub> = 4 mA, See Figure 1				0.4	V
V <sub>OL</sub>	Low-level output	voltage	$I_{OL}$ = 20 $\mu$ A, See Figure 1				0.1	v
V <sub>I(HYS)</sub>	Input voltage hys	teresis				150		mV
I <sub>IH</sub>	High-level input of	current	INI from O V/ to V/				10	
I <sub>IL</sub>	Low-level input c	urrent	IIN IIOM O A TO ACC	IN from 0 V to V <sub>CC</sub>				μΑ
Cı	Input capacitance	e to ground	IN at $V_{CC}$ , $V_{I} = 0.4 \sin (4E6\pi t)$			2		pF
CMTI	Common-mode to immunity	ransient	V <sub>I</sub> = V <sub>CC</sub> or 0 V, See Figure 5		25	50		kV/μs

<sup>(1)</sup> For the 5-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 4.5 V to 5.5 V. For the 3-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 3.15 V to 3.6 V.





## SWITCHING CHARACTERISTICS: $V_{\text{CC1}}$ at 5-V, $V_{\text{CC2}}$ at 3.3-V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	ISO724xC	See Figure 1	20		50	20
PWD	Pulse-width distortion <sup>(1)</sup>  t <sub>PHL</sub> - t <sub>PLH</sub>	150724xC				3	ns
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	ISO724xM		12		29	
PWD	Pulse-width distortion <sup>(1)</sup>  t <sub>PHL</sub> - t <sub>PLH</sub>				1	2	ns
	Dort to part alray (2)	ISO724xC				10	
t <sub>sk(pp)</sub>	Part-to-part skew <sup>(2)</sup>	ISO724xM			0	5	ns
	Channel to about a law (3)	ISO724xC				3	
t <sub>sk(o)</sub>	Channel-to-channel output skew (3)	ISO724xM			0	1	ns
t <sub>r</sub>	Output signal rise time		0		2		
t <sub>f</sub>	Output signal fall time		See Figure 1		2		ns
t <sub>PHZ</sub>	Propagation delay, high-level-to-high-impeda	ance output			15	20	
t <sub>PZH</sub>	Propagation delay, high-impedance-to-high-	level output	0		15	20	
t <sub>PLZ</sub>	Propagation delay, low-level-to-high-impeda	nce output	See Figure 2		15	20	ns
t <sub>PZL</sub>	Propagation delay, high-impedance-to-low-le	evel output			15	20	
t <sub>fs</sub>	Failsafe output delay time from input power	loss	See Figure 3		18		μS
t <sub>wake</sub>	Wake time from input disable		See Figure 4		15		μS
t <sub>jit(pp)</sub>	Peak-to-peak eye-pattern jitter	ISO724xM	150 Mbps PRBS NRZ data input, Same polarity input on all channels, See Figure 6		1		ns

<sup>(1)</sup> Also known as pulse skew

<sup>(2)</sup> t<sub>sk(pp)</sub> is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

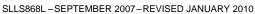
<sup>(3)</sup>  $t_{sk(0)}$  is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.



## ELECTRICAL CHARACTERISTICS: V<sub>CC1</sub> at 3.3-V, V<sub>CC2</sub> at 5-V<sup>(1)</sup> OPERATION

	PARAMETE	R	TEST CONDI	TIONS	MIN	TYP	MAX	UNIT	
SUPPL	Y CURRENT		•				•		
	10070400/84	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels,	no load, EN <sub>2</sub> at 3 V		0.5	1	^	
	ISO7240C/M	25 Mbps				3	5	mA	
	ISO7241C/M	Quiescent	$V_I = V_{CC}$ or 0 V, All channels, $EN_2$ at 3 V	no load, EN <sub>1</sub> at 3 V,		4	7	mA	
I <sub>CC1</sub>		25 Mbps				6.5	11		
	ISO724C/M	Quiescent	$V_I = V_{CC}$ or 0 V, All channels, $EN_2$ at 3 V	no load, EN <sub>1</sub> at 3 V,		6	10	mA	
		25 Mbps				9	14	1	
	10070400/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels,	no load, EN <sub>2</sub> at 3 V		15	22		
	ISO7240C/M	25 Mbps				17	25	mA	
loca	ISO7241C/M	Quiescent	$V_1 = V_{CC}$ or 0 V, All channels, no load, EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V			13	20	mA	
$I_{CC2}$		25 Mbps				18	28		
	ISO7242C/M	Quiescent	$V_I = V_{CC}$ or 0 V, All channels, EN <sub>2</sub> at 3 V	$V_1 = V_{CC}$ or 0 V, All channels, no load, EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V		10	16	mA	
		25 Mbps			15	24			
ELECT	RICAL CHARACTE	RISTICS							
I <sub>OFF</sub>	Sleep mode outp	out current	EN at 0 V, Single channel			0		μА	
			1 AmA Con Figure 1	ISO7240	V <sub>CC</sub> - 0.4				
$V_{OH}$	High-level output	tvoltage	I <sub>OH</sub> = -4 mA, See Figure 1	ISO724x (5-V side)	V <sub>CC</sub> - 0.8			V	
			$I_{OH} = -20 \mu A$ , See Figure 1		V <sub>CC</sub> - 0.1				
V	Low lovel output	voltogo	I <sub>OL</sub> = 4 mA, See Figure 1				0.4	V	
$V_{OL}$	Low-level output	voltage	$I_{OL}$ = 20 $\mu$ A, See Figure 1				0.1	V	
V <sub>I(HYS)</sub>	Input voltage hys	steresis				150		mV	
I <sub>IH</sub>	High-level input	current	IN from O V to V				10	^	
I <sub>IL</sub>	Low-level input of	urrent	IIN IIOM O V TO VCC	IN from 0 V to V <sub>CC</sub>				μΑ	
Cı	Input capacitanc	e to ground	IN at $V_{CC}$ , $V_{I} = 0.4 \sin (4E6\pi t)$	1		2		pF	
CMTI	Common-mode to immunity	ransient	V <sub>I</sub> = V <sub>CC</sub> or 0 V, See Figure 5		25	50		kV/μs	

<sup>(1)</sup> For the 5-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 4.5 V to 5.5 V. For the 3-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 3.15 V to 3.6 V.







## SWITCHING CHARACTERISTICS: $V_{\text{CC1}}$ at 3.3-V and $V_{\text{CC2}}$ at 5-V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	ISO724xC		22		51	no
PWD	Pulse-width distortion <sup>(1)</sup>  t <sub>PHL</sub> - t <sub>PLH</sub>	130724XC	Soo Figure 4			3	ns
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	100724vM	See Figure 1	12		30	
PWD	Pulse-width distortion <sup>(1)</sup>  t <sub>PHL</sub> - t <sub>PLH</sub>	ISO724xM			1	2	ns
	Dort to part alray (2)	ISO724xC				10	ns
t <sub>sk(pp)</sub>	Part-to-part skew (2)	ISO724xM			0	5	
	Character shared output along (3)	ISO724xC				2.5	
t <sub>sk(o)</sub>	Channel-to-channel output skew (3)	ISO724xM			0	1	ns
t <sub>r</sub>	Output signal rise time		Con Figure 4		2		
t <sub>f</sub>	Output signal fall time		See Figure 1		2		ns
t <sub>PHZ</sub>	Propagation delay, high-level-to-high-im	pedance output			15	20	
t <sub>PZH</sub>	Propagation delay, high-impedance-to-h	igh-level output			15	20	
t <sub>PLZ</sub>	Propagation delay, low-level-to-high-imp	edance output	See Figure 2		15	20	ns
t <sub>PZL</sub>	Propagation delay, high-impedance-to-lo	w-level output			15	20	
t <sub>fS</sub>	Failsafe output delay time from input por	wer loss	See Figure 3		12		μS
t <sub>wake</sub>	Wake time from input disable		See Figure 4		15		μS
t <sub>jit(pp)</sub>	Peak-to-peak eye-pattern jitter	ISO724xM	150 Mbps NRZ data input, Same polarity input on all channels, See Figure 6		1		ns

<sup>(1)</sup> Also known as pulse skew

<sup>(2)</sup> t<sub>sk(pp)</sub> is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

<sup>(3)</sup>  $t_{sk(0)}$  is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.



# ELECTRICAL CHARACTERISTICS: $V_{\text{CC1}}$ and $V_{\text{CC2}}$ at 3.3 $V^{(1)}$ OPERATION

PARAMETER			TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT			*		,	
	10070400/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, all channels, no load,		0.5	1	
	ISO7240C/M	25 Mbps	EN <sub>2</sub> at 3 V		3	5	mA
	ISO7241C/M	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, all channels, no load,		4	7	
I <sub>CC1</sub>		25 Mbps	EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V		6.5	11	A
	ISO7242C/M	Quiescent	$V_I = V_{CC}$ or 0 V, all channels, no load,		6	10	mA
		25 Mbps	EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V		9	14	
	ICO7240C/M	Quiescent	$V_I = V_{CC}$ or 0 V, all channels, no load,		9.5	15	A
	ISO7240C/M	25 Mbps	EN <sub>2</sub> at 3 V		10.5	17	mA
I <sub>CC2</sub>	ISO7241C/M	Quiescent	$V_I = V_{CC}$ or 0 V, all channels, no load,		8	13	mA
		25 Mbps	EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V		11.5	18	
	ISO7242C/M	Quiescent	$V_I = V_{CC}$ or 0 V, all channels, no load,		6	10	
		25 Mbps	EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V		9	14	
ELECTR	ICAL CHARACTERISTICS						
I <sub>OFF</sub>	Sleep mode output current		EN at 0 V, single channel		0		μΑ
1/	High lovel output voltage		$I_{OH} = -4$ mA, See Figure 1 $V_{CC} - 0.4$				V
V <sub>OH</sub> High-level output voltage			$I_{OH} = -20 \mu A$ , See Figure 1	V <sub>CC</sub> - 0.1			
V	Low-level output voltage		I <sub>OL</sub> = 4 mA, See Figure 1	0.4		0.4	V
$V_{OL}$	Low-level output voltage		$I_{OL}$ = 20 $\mu$ A, See Figure 1			\ \ \	
$V_{I(HYS)}$	Input voltage hysteresis				150		mV
I <sub>IH</sub>	High-level input current  Low-level input current		IN from 0 V or V <sub>CC</sub>			10	μА
I <sub>IL</sub>			IN THOM O V OI VCC	-10			μΛ
$C_{I}$	Input capacitance to ground		IN at $V_{CC}$ , $V_{I} = 0.4 \sin (4E6\pi t)$		2		pF
CMTI	Common-mode transient im	munity	V <sub>I</sub> = V <sub>CC</sub> or 0 V, See Figure 5	25	50		kV/μs

<sup>(1)</sup> For the 5-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 4.5 V to 5.5 V. For the 3-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 3.15 V to 3.6 V.



## SWITCHING CHARACTERISTICS: $V_{\text{CC1}}$ and $V_{\text{CC2}}$ at 3.3-V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	ISO724xC	100704-0			56	
PWD	Pulse-width distortion  t <sub>PHL</sub> - t <sub>PLH</sub>   <sup>(1)</sup>	150724xC	Con Figure 4			4	ns
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	100704-14	See Figure 1	12		34	
PWD	Pulse-width distortion  t <sub>PHL</sub> - t <sub>PLH</sub>   <sup>(1)</sup>	ISO724xM			1	2	ns
	Part-to-part skew (2)	ISO724xC				10	
t <sub>sk(pp)</sub>	Part-to-part skew (=)	ISO724xM			0	5	ns
t <sub>sk(o)</sub>	Channel to about a subset along (3)	ISO724xC				3.5	
	Channel-to-channel output skew (3)	ISO724xM			0	1	ns
t <sub>r</sub>	Output signal rise time	Soo Figure 1		2		ns	
t <sub>f</sub>	Output signal fall time		See Figure 1		2		ns
t <sub>PHZ</sub>	Propagation delay, high-level-to-high-impo	edance output			15	20	ns
t <sub>PZH</sub>	Propagation delay, high-impedance-to-hig	h-level output			15	20	
t <sub>PLZ</sub>	Propagation delay, low-level-to-high-impe	dance output	See Figure 2		15	20	
t <sub>PZL</sub>	Propagation delay, high-impedance-to-lov			15	20		
t <sub>fS</sub>	Failsafe output delay time from input pow	See Figure 3		18		μS	
t <sub>wake</sub>	Wake time from input disable	See Figure 4		15		μS	
t <sub>jit(pp)</sub>	Peak-to-peak eye-pattern jitter	ISO724xM	150 Mbps PRBS NRZ data input, same polarity input on all channels, See Figure 6		1		ns

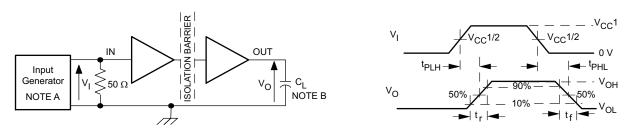
<sup>(1)</sup> Also referred to as pulse skew.

<sup>(2)</sup>  $t_{sk(pp)}$  is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

<sup>(3)</sup>  $t_{sk(0)}$  is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.

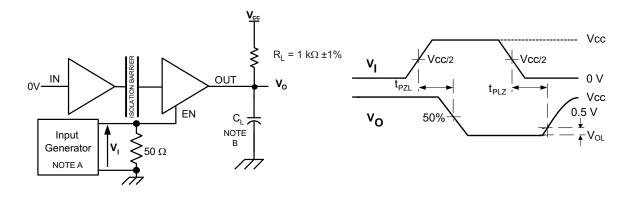


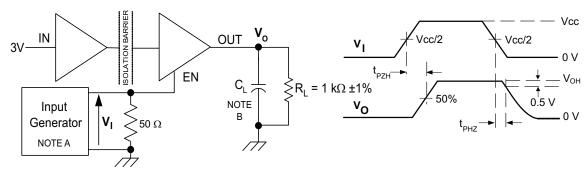
#### PARAMETER MEASUREMENT INFORMATION



- A. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  50 kHz, 50% duty cycle,  $t_r \leq$  3 ns,  $t_f \leq$  3 ns,  $Z_O = 50\Omega$ .
- B.  $C_L = 15$  pF and includes instrumentation and fixture capacitance within  $\pm 20\%$ .

Figure 1. Switching Characteristic Test Circuit and Voltage Waveforms



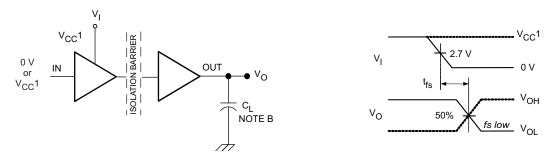


- A. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  50 kHz, 50% duty cycle,  $t_r \leq$  3 ns,  $t_f \leq$  3 ns,  $Z_O = 50\Omega$ .
- B.  $C_L = 15$  pF and includes instrumentation and fixture capacitance within  $\pm 20\%$ .

Figure 2. Enable/Disable Propagation Delay Time Test Circuit and Waveform

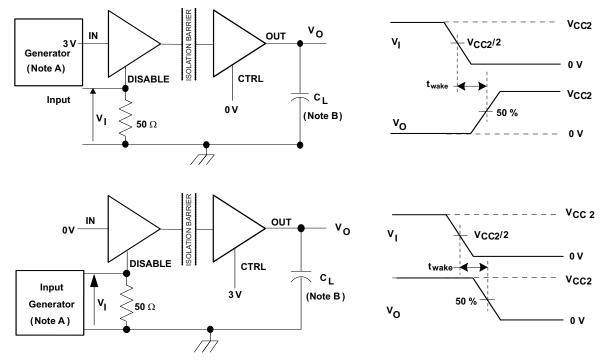


#### PARAMETER MEASUREMENT INFORMATION (continued)



- A.  $C_L = 15$  pF and includes instrumentation and fixture capacitance within  $\pm 20\%$ .
- B. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  50 kHz, 50% duty cycle,  $t_r \leq$  3 ns,  $t_f \leq$  3 ns,  $Z_O = 50\Omega$ .

Figure 3. Failsafe Delay Time Test Circuit and Voltage Waveforms



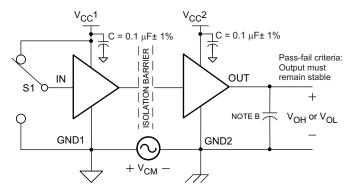
NOTE: Which ever test yields the longest time is used in this datasheet

A. Whichever test yields the longest time is used in this data sheet.

Figure 4. Wake Time From Input Disable Test Circuit and Voltage Waveforms

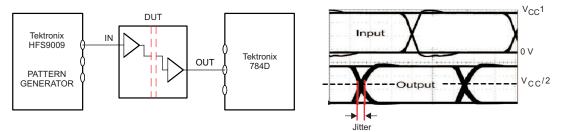


#### PARAMETER MEASUREMENT INFORMATION (continued)



- A.  $C_L = 15 \text{ pF}$  and includes instrumentation and fixture capacitance within  $\pm 20\%$ .
- B. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  50 kHz, 50% duty cycle,  $t_r \leq$  3 ns,  $t_f \leq$  3 ns,  $Z_O = 50\Omega$ .

Figure 5. Common-Mode Transient Immunity Test Circuit and Voltage Waveform



NOTE: PRBS bit pattern run length is  $2^{16} - 1$ . Transition time is 800 ps. NRZ data input has no more than five consecutive 1s or 0s.

Figure 6. Peak-to-Peak Eye-Pattern Jitter Test Circuit and Voltage Waveform

#### **DEVICE INFORMATION**

#### **PACKAGE CHARACTERISTICS**

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	TINU
L(I01)	Minimum air gap (Clearance)	Shortest terminal-to-terminal distance through air	8.34			mm
L(102)	Minimum external tracking (Creepage)	Shortest terminal-to-terminal distance across the package surface	8.1			mm
C <sub>TI</sub>	Tracking resistance (comparative tracking index)	DIN IEC 60112/VDE 0303 Part 1	≥ 175			<b>V</b>
	Minimum Internal Gap (Internal Clearance)	Distance through the insulation	0.008			mm
R <sub>IO</sub>	Isolation resistance	Input to output, $V_{IO}$ = 500 V, all pins on each side of the barrier tied together creating a two-terminal device		>10 <sup>12</sup>		Ω
C <sub>IO</sub>	Barrier capacitance Input to output	$V_I = 0.4 \sin (4E6\pi t)$		2		pF
C <sub>I</sub>	Input capacitance to ground	$V_I = 0.4 \sin (4E6\pi t)$		2		pF



#### **IEC 60664-1 RATINGS TABLE**

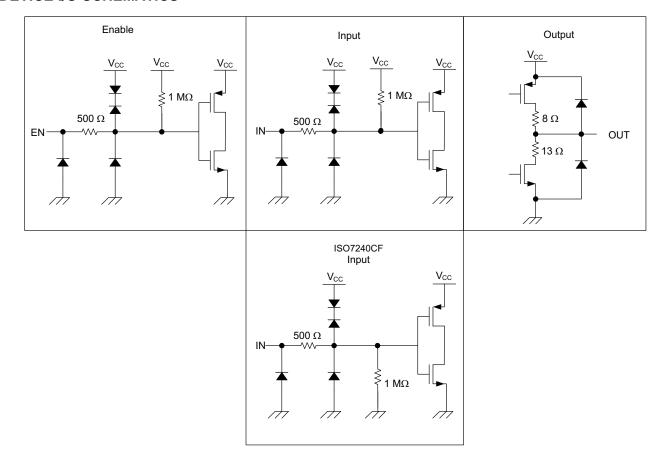
PARAMETER	TEST CONDITIONS	SPECIFICATION
Basic isolation group	Material group	Illa
Installation alongification	Rated mains voltage ≤150 VRMS	I-IV
Installation classification	Rated mains voltage ≤300 VRMS	I-III

#### **REGULATORY INFORMATION**

VDE	CSA	UL		
Certified according to IEC 60747-5-2	Approved under CSA Component Acceptance Notice	Recognized under 1577 Component Recognition Program <sup>(1)</sup>		
File Number: 40016131	File Number: 1698195	File Number: E181974		

(1) Production tested ≥ 3000 Vrms for 1 second in accordance with UL 1577.

#### **DEVICE I/O SCHEMATICS**





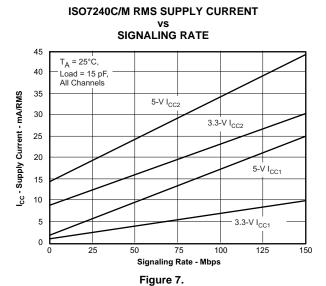
#### THERMAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
θ <sub>JA</sub> Junction-to-air	Low-K Thermal Resistance <sup>(1)</sup>		168		°C/W	
	Junction-to-all	High-K Thermal Resistance	96.1			C/VV
$\theta_{JB}$	Junction-to-Board Thermal Resistance			61		°C/W
$\theta_{\text{JC}}$	Junction-to-Case Thermal Resistance			48		°C/W
P <sub>D</sub>	Device Power Dissipation	V <sub>CC1</sub> = V <sub>CC2</sub> = 5.5 V, T <sub>J</sub> = 150°C, C <sub>L</sub> = 15 pF, Input a 50% duty cycle square wave			220	mW

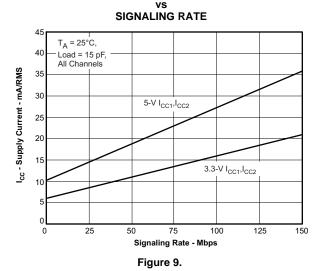
<sup>(1)</sup> Tested in accordance with the Low-K or High-K thermal metric definitions of EIA/JESD51-3 for leaded surface mount packages.

#### TYPICAL CHARACTERISTIC CURVES





ISO7242C/M RMS SUPPLY CURRENT



ISO7241C/M RMS SUPPLY CURRENT
vs

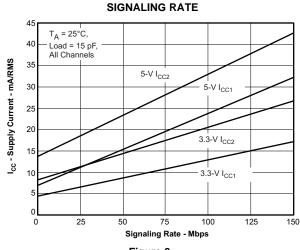


Figure 8.



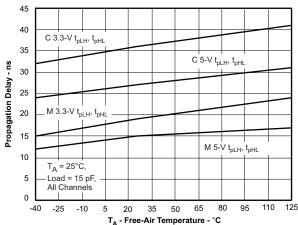


Figure 10.



#### **TYPICAL CHARACTERISTIC CURVES (continued)**



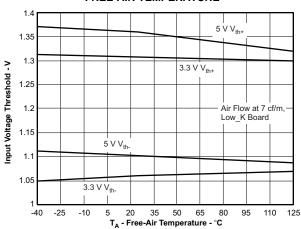


Figure 11.

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#### HIGH-LEVEL OUTPUT CURRENT vs HIGH-LEVEL OUTPUT VOLTAGE

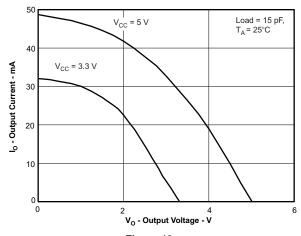


Figure 13.

#### V<sub>CC1</sub> FAILSAFE THRESHOLD vs FREE-AIR TEMPERATURE

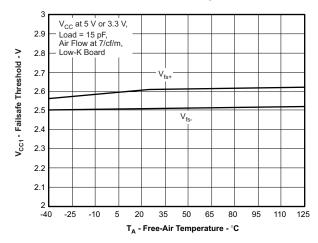


Figure 12.

# LOW-LEVEL OUTPUT CURRENT vs LOW-LEVEL OUTPUT VOLTAGE

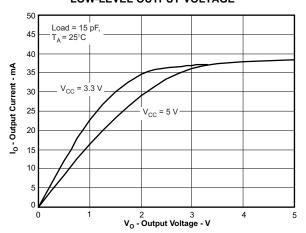


Figure 14.



#### **APPLICATION INFORMATION**

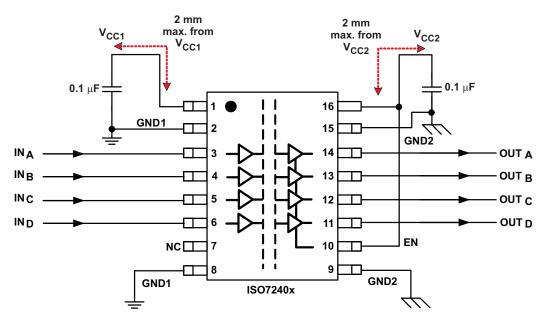


Figure 15. Typical ISO7240x Application Circuit

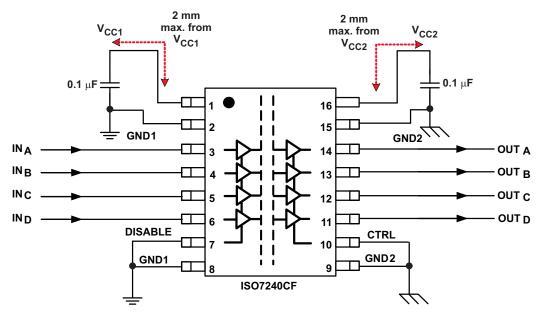


Figure 16. Typical ISO7240CF Failsafe-Low Application Circuit



#### LIFE EXPECTANCY vs. WORKING VOLTAGE

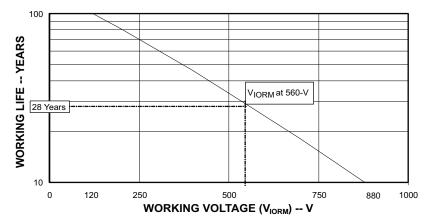


Figure 17. Time-Dependant Dielectric Breakdown Testing Results

#### **REVISION HISTORY**

CI	hanges from Original (September 2007) to Revision A	Page
•	Deleted Product Preview note	2
•	Changed V <sub>CC</sub> Supply Voltage in the ROC Table From: 3.6 To: 3.45	3
•	Changed V <sub>CC</sub> Supply Voltage in the ROC Table From: 3 To: 3.15	3
•	Changed TBDs to actual values.	
•	Changed C <sub>I</sub> - typ value From: 1 To: 2	4
•	Changed Propagation delay max From: 22 To: 23	5
•	Changed C <sub>1</sub> - typ value From: 1 To: 2	6
•	Changed Propagation delay max From: 46 To: 50	7
•	Changed Propagation delay max From: 28 To: 29	7
•	Changed ISO724xA/C max value From: 2.5 To: 3	7
•	Changed C <sub>I</sub> - typ value From: 1 To: 2	8
•	Changed Propagation delay max From: 26 To: 30	9
•	Changed typ value From: 1 To: 2	10
•	Changed Propagation delay max From: 32 To: 34	11
•	Changed ISO724xA/C max value From: 3 To: 3.5	11
•	Changed C <sub>IO</sub> - typ value From: 1 To: 2	14
•	Changed C <sub>I</sub> - typ value From: 1 To: 2	14
•	Changed the REGULATORY INFORMATION Table	15
<u>•</u>	Changed Figure 7, Figure 8, and Figure 10. Added Figure 9.	16
CI	hanges from Revision A (December 2007) to Revision B	Page
•	Changed V <sub>CC</sub> Supply Voltage in the ROC Table From: 3.45 To: 3.6	3
CI	hanges from Revision B (August 2008) to Revision C	Page
•	Deleted Min = 4.5 V and max = 5.5 V for Supply Voltage of the ROC Table	
•	Changed V <sub>CC</sub> Supply Voltage in the ROC Table From: 3.6 To: 5.5	
_		



Changes from Revision C (April 2008) to Revision D	Page
Changed Feature Bullet 4000-V <sub>peak</sub> Isolation	1
Added t <sub>sk(pp)</sub> Part-to-part skew	
Changed Typical ISO724x Application Circuit Figure 15	
Changes from Revision D (April 2008) to Revision E	Page
<ul> <li>Added table note: or the 5-V operation, V<sub>CC1</sub> or V<sub>CC2</sub> is specified from</li> </ul>	4.5 V to 5.5 V
<ul> <li>Added table note: or the 5-V operation, V<sub>CC1</sub> or V<sub>CC2</sub> is specified from</li> </ul>	
<ul> <li>Added table note: or the 5-V operation, V<sub>CC1</sub> or V<sub>CC2</sub> is specified from</li> </ul>	
<ul> <li>Added table note: or the 5-V operation, V<sub>CC1</sub> or V<sub>CC2</sub> is specified from</li> </ul>	
<ul> <li>Added table note: or the 5-V operation, V<sub>CC1</sub> or V<sub>CC2</sub> is specified from</li> </ul>	
Changes from Revision E (May 2008) to Revision F	Page
Changed Title From: QUAD DIGITAL ISOLATORS To: HIGH SPEED	QUAD DIGITAL ISOLATORS 1
• Deleted ISO724xA devices. See SLLS905 for the ISO7240A, ISO724	1A, and ISO7242A 1
Changed Feature Low Jitter Content - From: 1, 25, and 150-Mbps Sig Signaling Rate Options	· · · · · · · · · · · · · · · · · · ·
Added t <sub>sk(pp)</sub> footnote.	5
Added t <sub>sk(o)</sub> footnote.	
Added t <sub>sk(pp)</sub> footnote.	
Added t <sub>sk(o)</sub> footnote.	
Changes from Revision F (May 2008) to Revision G	Page
Changed the PACKAGE CHARACTERISTICS table, line , L <sub>(IO1)</sub> MIN v	
Onangou tio i Mora tee en material rice table, iiile , E(ioi) iiili v	uide 1101117 7 7 11111 10 0.0 1111111 1 1 1 1 1 1 1 1 1
Changes from Revision G (July 2008) to Revision H	Page
Added Device number ISO7240CF.	
Added Features Bullet: Selectable Failsafe Output (ISO7240CF)	1
Changed description paragraph 4 text	
Added for device number ISO7240CF.	2
• Changed V <sub>I</sub> in the Abs Max Table From: Voltage at IN, OUT, EN To: \	/oltage at IN, OUT, EN, DISABLE, CTRL 3
Added t <sub>wake</sub> , Wake time from input disable	5
Added t <sub>wake</sub> , Wake time from input disable	
Added t <sub>wake</sub> , Wake time from input disable	
Added t <sub>wake</sub> , Wake time from input disable	11
Changes from Revision H (October 2008) to Revision I	Page
<ul> <li>Added information to the Features bullet to include CSA and IEC 6095</li> </ul>	50-1 certification 1



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**INSTRUMENTS** 

SLLS868L - SEPTEMBER 2007-REVISED JANUARY 2010

Changes from Revision I (December 2008) to Revision J							
Changed I <sub>CC1</sub> for Quiescent and 1Mbps From: 10mA To: 11mA	4						
Changed I <sub>CC1</sub> for Quiescent and 1Mbps From: 10mA To: 11mA	6						
Changes from Revision J (April 2009) to Revision K	Page						
Changed the Input circuit in the DEVICE I/O SCHEMATICS illustration	15						
Changes from Revision K (Decemberl 2009) to Revision L	Page						
Added the IEC 60747-5-2 INSULATION CHARACTERISTIC table	3						
$\bullet  \text{Added $C_{\text{TI}}$ - Tracking resistance (comparative tracking index to the PACKAGE CHARACTERISTICS table \ \dots \dots \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ $	14						
Added the IEC 60664-1 RATINGS TABLE	15						



16-Jun-2010

#### **PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan <sup>(2)</sup>	Lead/ Ball Finish	MSL Peak Temp <sup>(3)</sup>	Samples (Requires Login)
ISO7240CDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Sample
ISO7240CDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Sample
ISO7240CDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Purchase Samples
ISO7240CDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Purchase Samples
ISO7240CFDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Contact TI Distributo or Sales Office
ISO7240CFDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Contact TI Distributo or Sales Office
ISO7240CFDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Sampl
ISO7240CFDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Sampl
ISO7240MDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Sampl
ISO7240MDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Sample
ISO7240MDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Purchase Samples
ISO7240MDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Purchase Samples
ISO7241CDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Sampl
ISO7241CDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Sampl
ISO7241CDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Contact TI Distribute or Sales Office
ISO7241CDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Contact TI Distribute or Sales Office
ISO7241MDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Sampl





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Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan <sup>(2)</sup>	Lead/ Ball Finish	MSL Peak Temp <sup>(3)</sup>	Samples (Requires Login)
ISO7241MDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Samples
ISO7241MDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Contact TI Distributor or Sales Office
ISO7241MDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Contact TI Distributor or Sales Office
ISO7242CDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Samples
ISO7242CDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Samples
ISO7242CDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Contact TI Distributor or Sales Office
ISO7242CDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Contact TI Distributor or Sales Office
ISO7242MDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Samples
ISO7242MDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Request Free Samples
ISO7242MDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Contact TI Distributor or Sales Office
ISO7242MDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	Contact TI Distributor or Sales Office

<sup>&</sup>lt;sup>(1)</sup> The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.



#### PACKAGE OPTION ADDENDUM

16-Jun-2010

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

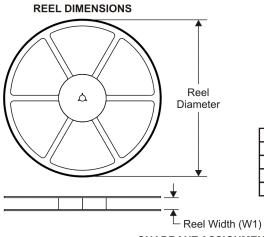
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## PACKAGE MATERIALS INFORMATION

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#### TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO7240CDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7240CFDWR	SOIC	DW	16	2000	330.0	16.4	10.9	10.78	3.0	12.0	16.0	Q1
ISO7240MDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7241CDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7241MDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7242CDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7242MDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1

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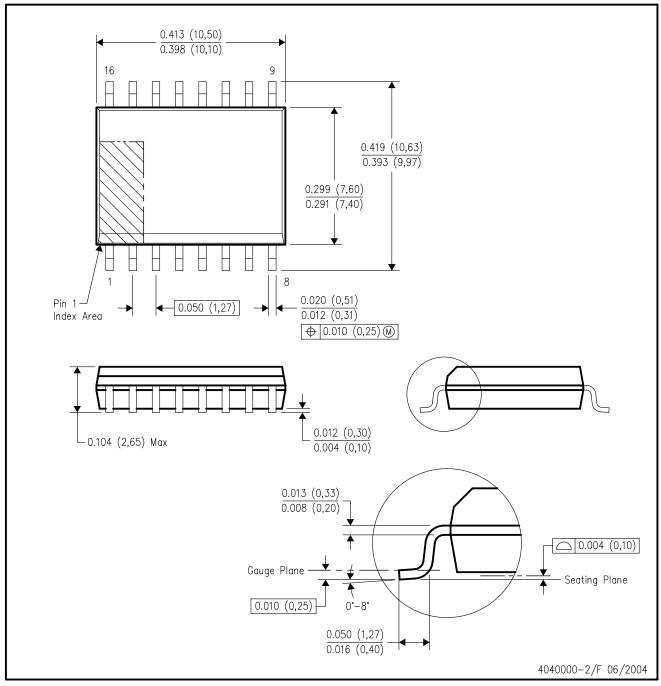


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO7240CDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7240CFDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7240MDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7241CDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7241MDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7242CDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7242MDWR	SOIC	DW	16	2000	358.0	335.0	35.0

# DW (R-PDSO-G16)

## PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AA.



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